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<b>Notice of References Cited</b>	Application/Control No. 09/815,337	Applicant(s)/Patent Under Reexamination CEDERVALL ET AL.	
	Examiner Nawara T. Omary	Art Unit 2683	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-5,973,643	10-1999	Hawkes et al.	342/457
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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